

Dual N-Channel Logic Level Enhancement Mode Field Effect Transistor

Product Summary:

	N-CH-Q1	N-CH-Q2
BV_{DSS}	30V	30V
$R_{DS(on)} (MAX.)$	5.7m Ω	2.2m Ω
I_D	48A	90A

Dual N Channel MOSFET

UIS, Rg 100% Tested

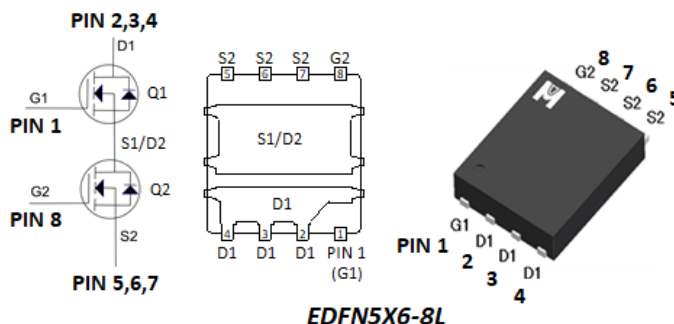
RoHS & Halogen Free & TSCA Compliant

ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS		UNIT
			Q1	Q2	
Gate-Source Voltage		V_{GS}	± 20	± 12	V
Continuous Drain Current	$T_C = 25^\circ\text{C}$	I_D	48	90	A
	$T_A = 25^\circ\text{C} (t \leq 10s)$		18	29	
	$T_A = 25^\circ\text{C} (\text{Steady-State})$		14	23	
	$T_C = 100^\circ\text{C}$		30	57	
Pulsed Drain Current ¹		I_{DM}	100	250	
Avalanche Current		I_{AS}	35	60	
Avalanche Energy	$L = 0.1\text{mH}, R_G = 25\Omega$	E_{AS}	61	180	mJ
Repetitive Avalanche Energy ²	$L = 0.05\text{mH}$	E_{AR}	30	90	
Power Dissipation	$T_C = 25^\circ\text{C}$	P_D	21	40	W
	$T_C = 100^\circ\text{C}$		8	16	
Operating Junction & Storage Temperature Range		T_J, T_{stg}	-55 to 150		$^\circ\text{C}$

100% UIS testing in condition of Q1 $V_D = 25\text{V}$, $L = 0.1\text{mH}$, $V_G = 10\text{V}$, $I_L = 21\text{A}$, Rated $V_{DS} = 30\text{V}$ N-CH

100% UIS testing in condition of Q2 $V_D = 25\text{V}$, $L = 0.1\text{mH}$, $V_G = 10\text{V}$, $I_L = 36\text{A}$, Rated $V_{DS} = 30\text{V}$ N-CH



THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL		TYPICAL	MAXIMUM		UNIT
Junction-to-Case	$R_{\theta JC}$	Steady State		5.8	3.1	°C / W
Junction-to-Ambient	$R_{\theta JA}$	Steady State		65	65	
	$R_{\theta JA}$	$t \leq 10 \text{ s}$		40	40	

¹Pulse width limited by maximum junction temperature.

²Duty cycle < 1%

³The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^\circ\text{C}$.

⁴Guarantee by Engineering test.

ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS				UNIT	
			MIN	TYP	MAX			
STATIC								
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	Q1	30			V	
			Q2	30				
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	Q1	1	1.5	3		
			Q2	1	1.5	3		
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 20V$	Q1			± 100	nA	
		$V_{DS} = 0V, V_{GS} = \pm 12V$	Q2			± 100		
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 24V, V_{GS} = 0V$	Q1			1	μA	
			Q2			1		
		$V_{DS} = 20V, V_{GS} = 0V, T_J = 125^\circ C$	Q1			25		
			Q2			25		
On-State Drain Current ¹	$I_{D(ON)}$	$V_{DS} = 10V, V_{GS} = 10V$	Q1	48			A	
			Q2	90				
Drain-Source On-State Resistance ¹	$R_{DS(ON)}$	$V_{GS} = 10V, I_D = 20A$	Q1		5.0	5.7	mΩ	
		$V_{GS} = 10V, I_D = 20A$	Q2		1.8	2.2		
		$V_{GS} = 4.5V, I_D = 20A$	Q1		7.0	8.8		
		$V_{GS} = 4.5V, I_D = 20A$	Q2		2.6	3.4		
Forward Transconductance ¹	g_{fs}	$V_{DS} = 5V, I_D = 20A$	Q1		48		S	
		$V_{DS} = 5V, I_D = 20A$	Q2		72			
DYNAMIC								
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 15V, f = 1MHz$	Q1		1327		pF	
			Q2		3770			
Output Capacitance	C_{oss}		Q1		430			
			Q2		1122			
Reverse Transfer Capacitance	C_{rss}		Q1		37			
			Q2		82			
Gate Resistance	R_g	$V_{GS} = 15mV, V_{DS} = 0V, f = 1MHz$	Q1		1.1		Ω	
			Q2		1.3			
Total Gate Charge ^{1,2}	$Q_g(V_{GS}=10V)$	$V_{DD} = 15V, V_{GS} = 10V, I_D = 20A$	Q1		22			
	$Q_g(V_{GS}=4.5V)$		Q2		56			
			Q1		11			
			Q2		26			



Gate-Source Charge ^{1,2}	Q _{gs}	V _{DD} = 15V, V _{GS} = 10V, I _D = 20A	Q1		3		nC
			Q2		7.1		
Gate-Drain Charge ^{1,2}	Q _{gd}		Q1		4.3		
			Q2		8.8		
Turn-On Delay Time ^{1,2}	t _{d(on)}	V _{DD} = 15V, I _D = 5A, V _{GS} = 10V, R _G = 3Ω	Q1		6.3		nS
			Q2		11.3		
Rise Time ^{1,2}	t _r		Q1		11.3		
			Q2		17.7		
Turn-Off Delay Time ^{1,2}	t _{d(off)}		Q1		40		
			Q2		105.3		
Fall Time ^{1,2}	t _f		Q1		16.2		
			Q2		41.4		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (T _J = 25 °C)							
Continuous Current	I _S		Q1			20	A
			Q2			30	
Pulsed Current ³	I _{SM}		Q1			80	
			Q2			120	
Forward Voltage ¹	V _{SD}	I _F = 10A, V _{GS} = 0V	Q1			1.2	V
			Q2			1.2	
Reverse Recovery Time	t _{rr}	Q1 I _F = 20A, dI _F /dt = 100A / μS	Q1		30		nS
			Q2		35		
Reverse Recovery Charge	Q _{rr}	Q2 I _F = 20A, dI _F /dt = 100A / μS	Q1		18		nC
			Q2		25		

¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.

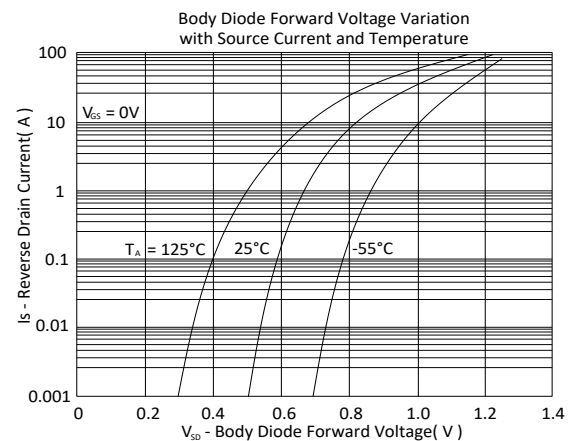
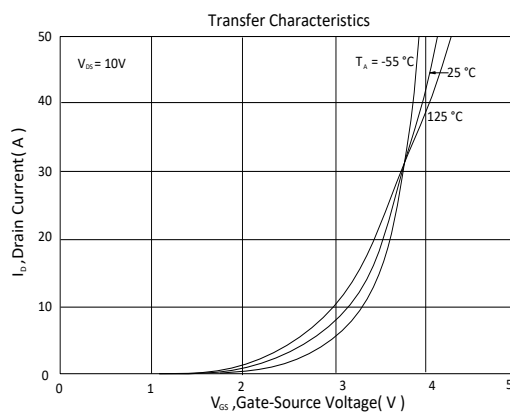
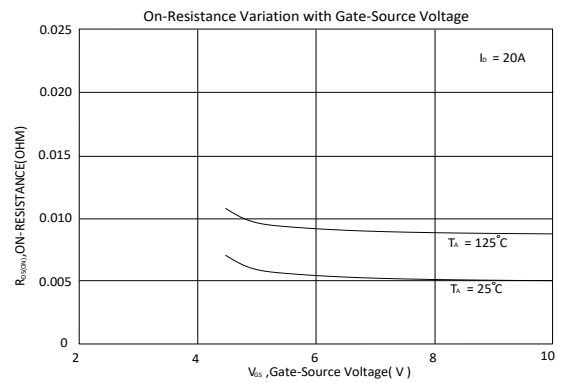
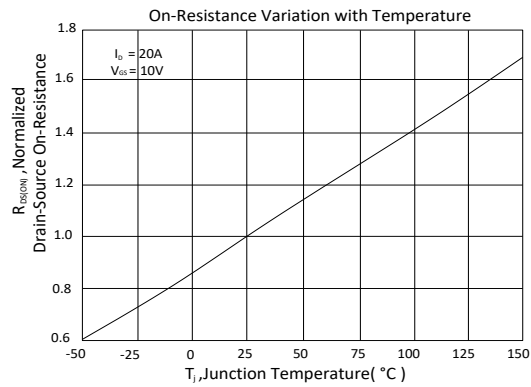
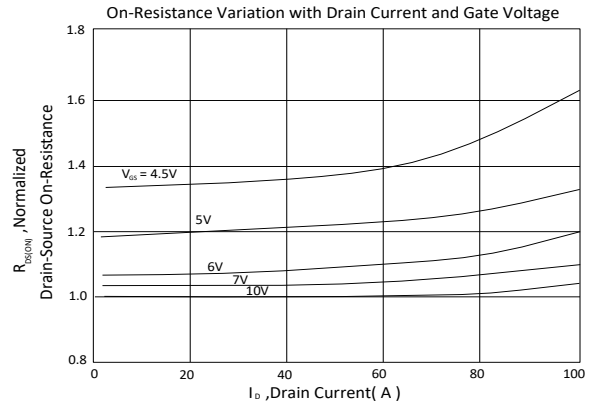
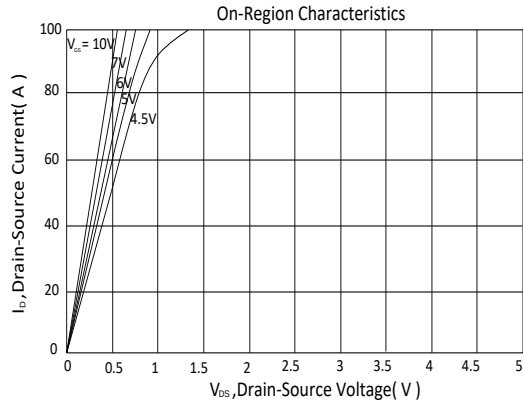
²Independent of operating temperature.

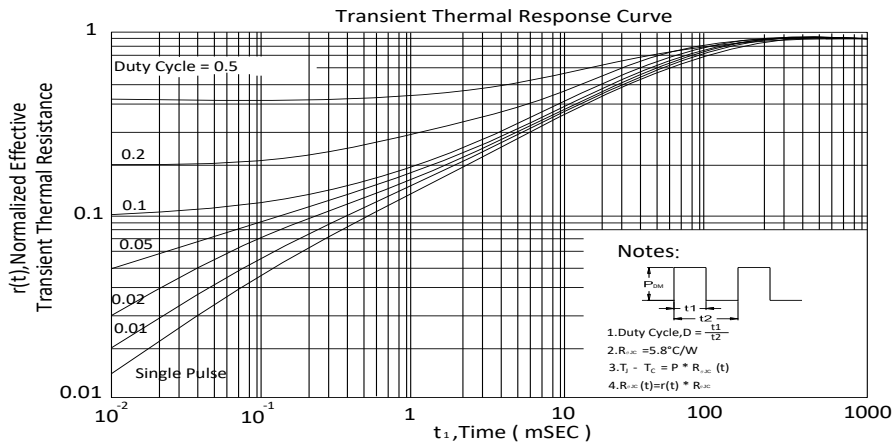
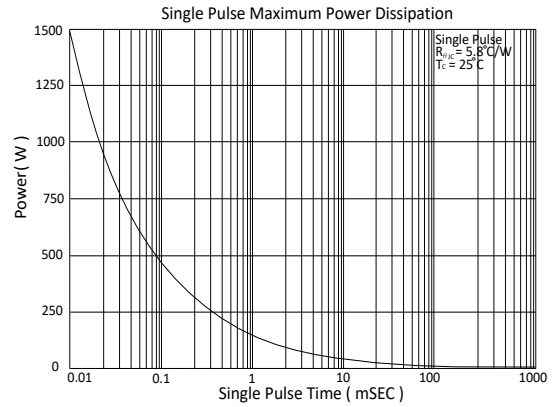
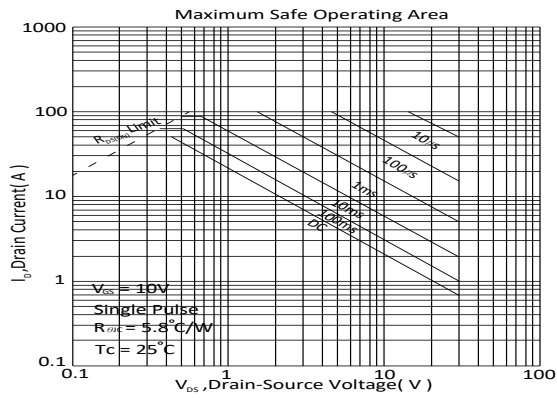
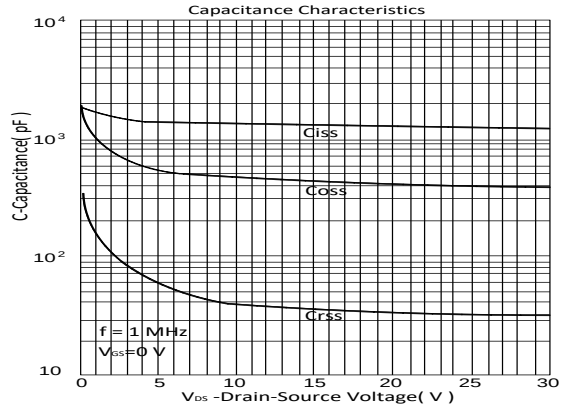
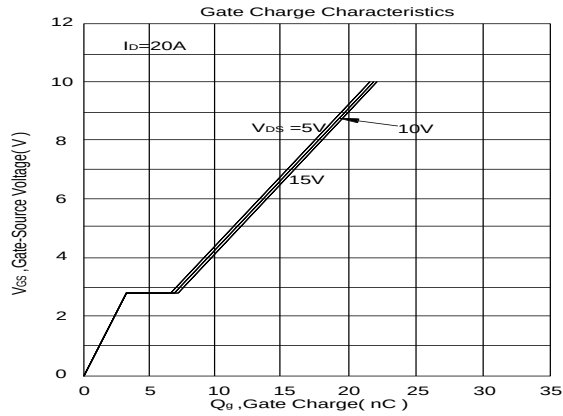
³Pulse width limited by maximum junction temperature.

EMC will review datasheet by quarter, and update new version.



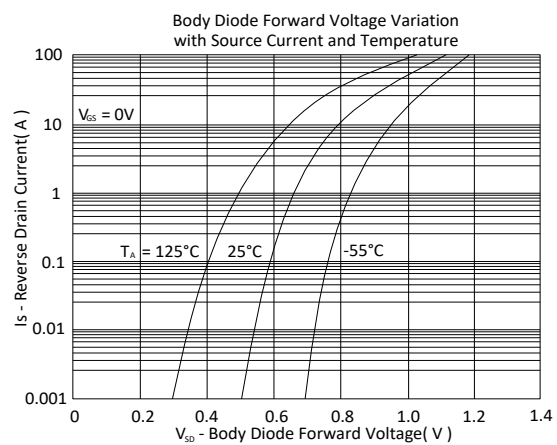
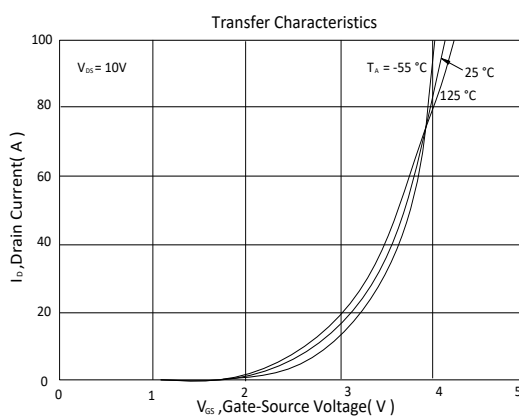
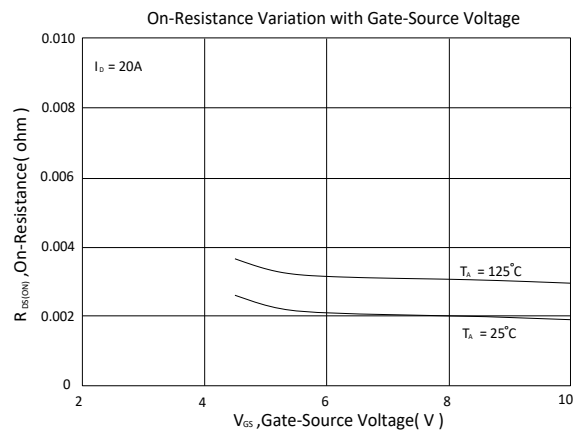
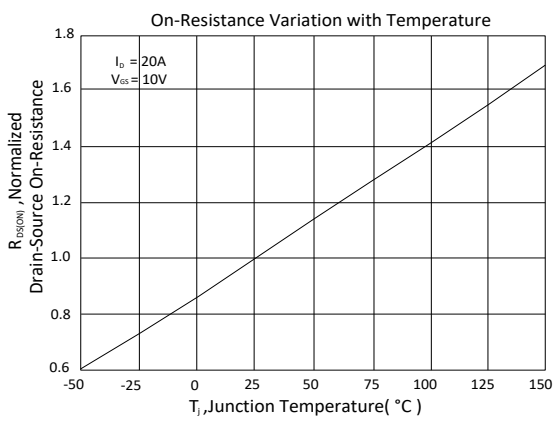
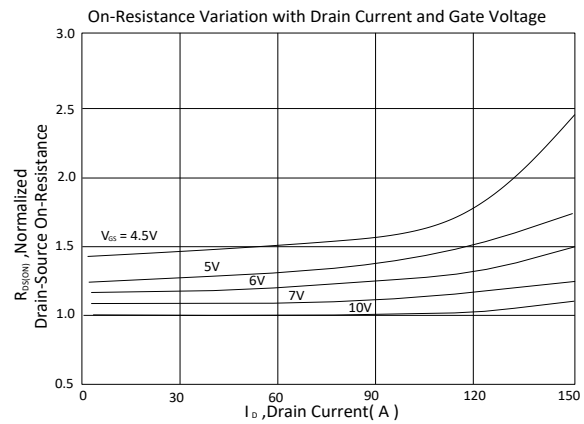
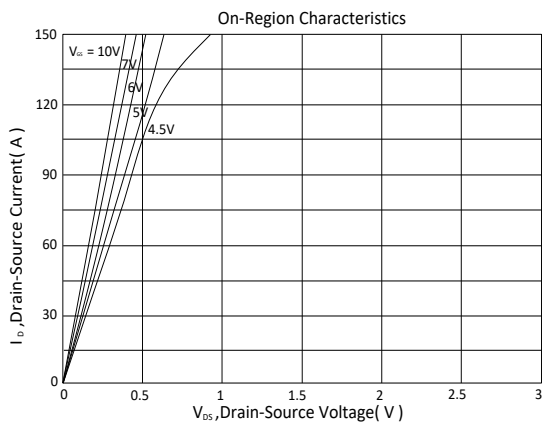
Q1 TYPICAL CHARACTERISTICS

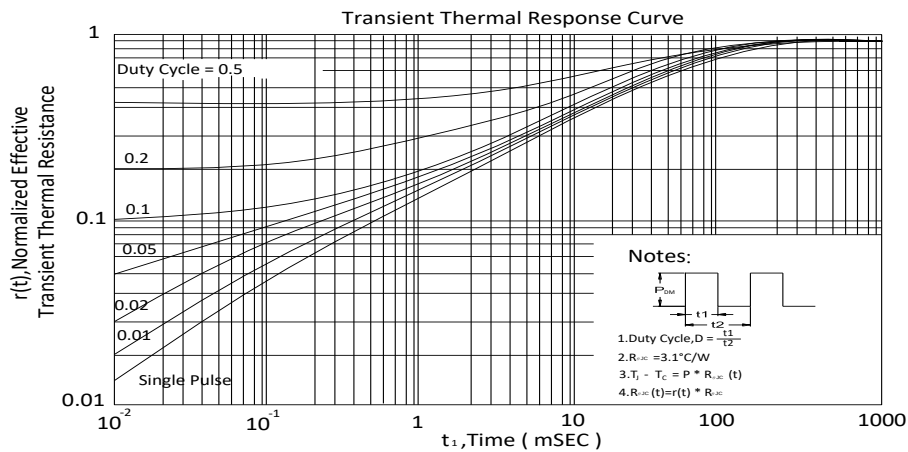
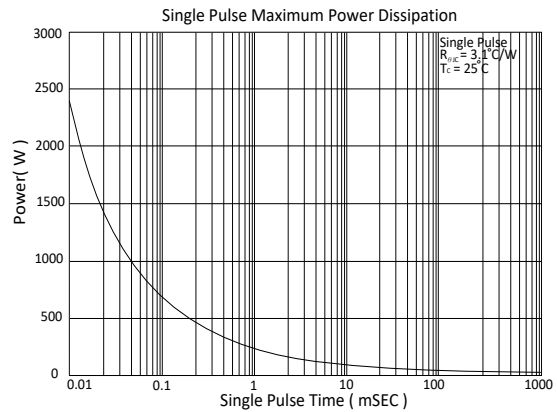
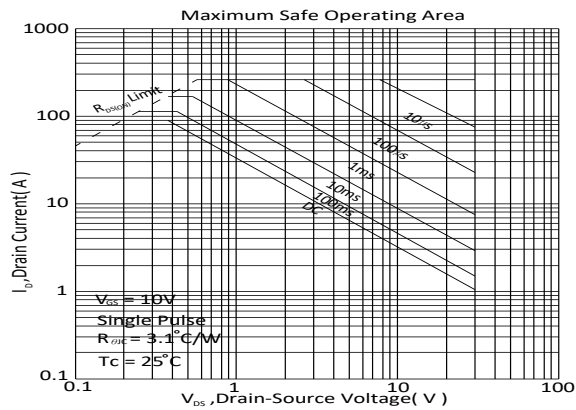
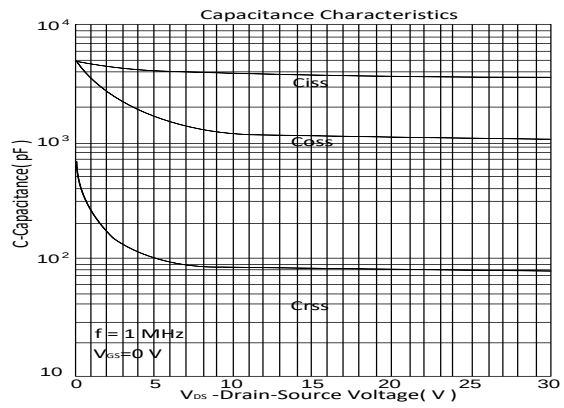
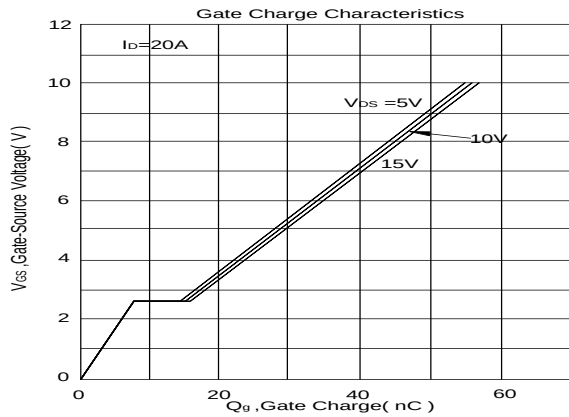






Q2 TYPICAL CHARACTERISTICS





Ordering & Marking Information

Device Name: EMP19K03HPCS for Asymmetric Dual EDFN5X6



EMP19K03HPCS: Device Name

ABCDEFG: Date Code

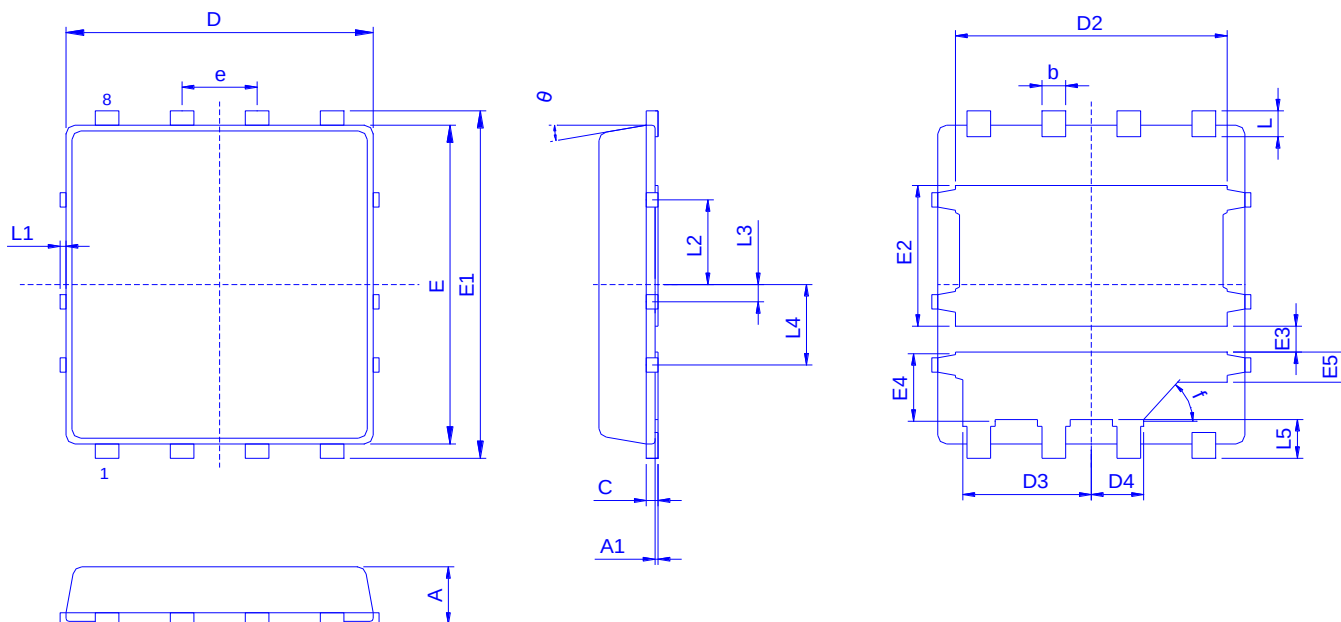
A: Assembly House

B: Year(A:2008 B:2009 C:2010....)

C: Month(A:01 B:02 C:03 D:04 E:05 F:06 G:07 H:08 I:09 J:10 K:11 L:12)

DEFG: Serial No.

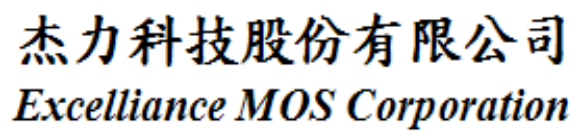
Outline Drawing



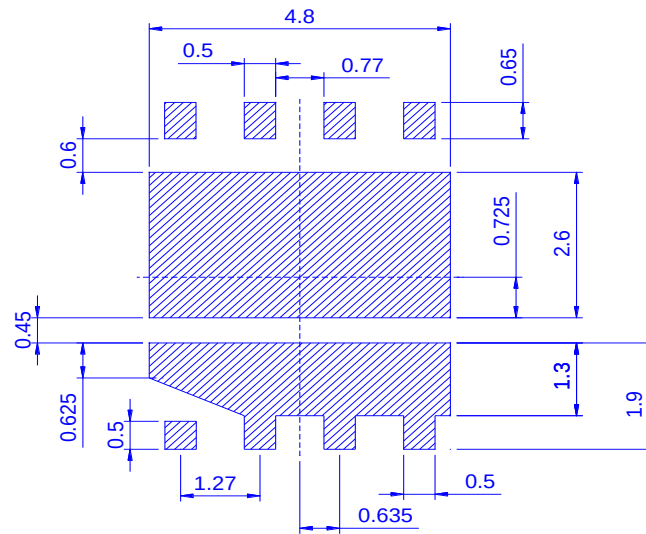
Dimension in mm

Dimension	A	A1	b	c	D	D2	D3	D4	E	E1	E2	E3	E4	E5
Min.	0.85	0.00	0.35	0.15		4.5	2.125	0.835			2.4	0.40	1.125	0.475
Typ.	0.90		0.40	0.20	5.2	4.6	2.175	0.885	5.55	6.05	2.45	0.45	1.175	0.525
Max.	1.00	0.05	0.45	0.25		4.7	2.225	0.935			2.5	0.50	1.225	0.575

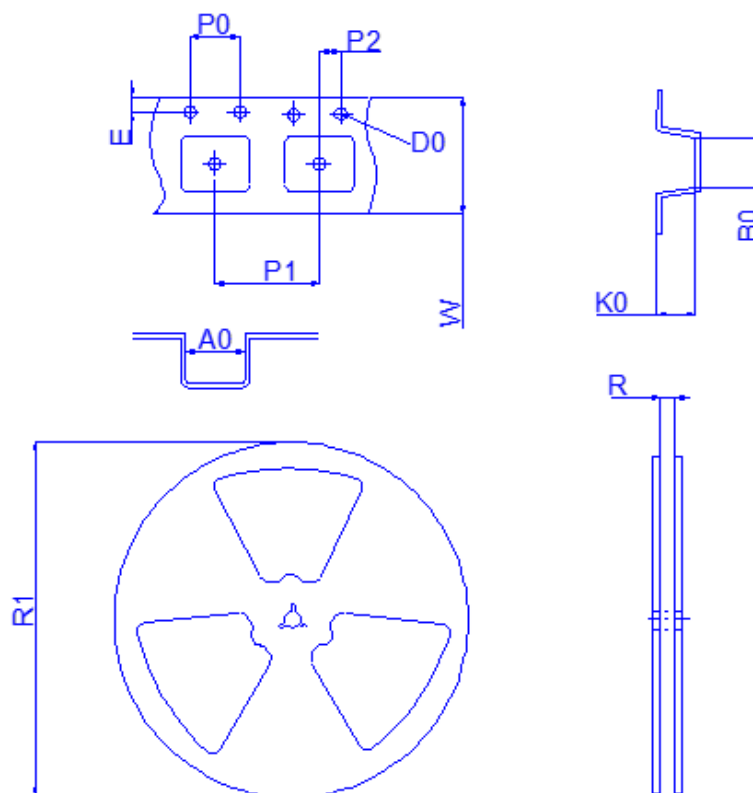
Dimension	e	L	L1	L2	L3	L4	L5	F	θ
Min.		0.35	0	1.375	0.2	1.3	0.575		0°
Typ.	1.27	0.45		1.475	0.3	1.4	0.675	45°	
Max.		0.55	0.1	1.575	0.4	1.5	0.775		10°



Recommended minimum pads



◆ **Tape&Reel Information:**2500pcs/Reel(Dimension in millimeter)



Package	EDFN5X6
Reel	13"
Device orientation	FEED DIRECTION

Dimension in mm

Dimension	Carrier tape									Reel	
	A0	B0	D0	E	K0	P0	P1	P2	W	R	R1
Typ.	6.4	5.3	1.5	1.8	1.6	4.0	8.0	2.0	12.0	12.4	330.0
±	0.2	0.2	0.1	0.1	0.6	0.1	0.1	0.1	0.3	2.0	2.0